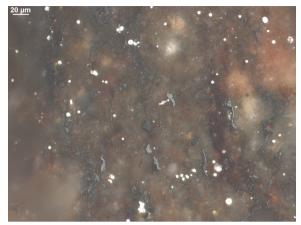
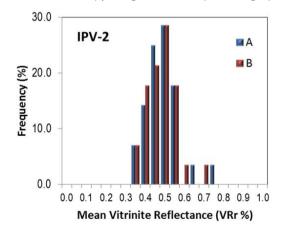
Sample Analyzed for DOMVR in the Commission II of the ICCP



Insert a microscopy image of the sample with graphic scale



Insert the distribution of vitrinite reflectance means

| | Sample In | Sample Information | | | | |
|--|------------------|-----------------------------------|---------------|---------------|----------------------------|--|
| | Code: 2 | | Year of Analy | /sis: 2012-20 | D13 ICCP | |
| | Type of Sam | ple: Outcrop | | | | |
| Location and/or Fm.: Texas, Boquillas Formation (equiv. to Eagle Ford) | | | | | | |
| | Country: | USA | Age | (Period): Upp | per Cretaceous | |
| | Dep. Enviro | nment: Marine | | | | |
| | Coordinates | Long101.2362 | Coordin | ates Lat. 29. | .709683 | |
| ICCP WG: Identification of Primary Vitrinite | | | | | | |
| Convenor: | Paul C. Hackley | Hackley E-mail: phackley@usgs.gov | | | | |
| Exercise I | nformation | | | | lata Available | |
| Report: Hac | kley 2013 | Participants N: | 28 | ☐ Chen | nical Analysis Eval | |
| Group Mean (VRr%) 0.51/0.51 Group Stdv.: 0.088/0.0 | | | 38/0.079 | Spec | tral Fluorescence erals | |
| Averaged Unsigned Multiple Stdv.: 0.71/0.75 | | | | | chemistry Jes available | |
| Coef. of Vari | ation: 17.2/15.6 | Scattering Index: | 0.6/0.6 | l X | ers (indicate in ments) | |
| | | | | | | |

Comments:

Twenty-eight participants reported measurements in duplicate. Participants acknowledged that all measurements were on vitrinite; bitumen is present with lower reflectance (0.25%) but was not measured by any participant. X-ray diffraction data is available for this sample. Sample contains fluorescent bitumens and fluorescent telalginite. Vitrinite, inertinite, and solid bitumen are abundant; planktic forams filled by bitumen are abundant. AOM is relatively abundant; fluorescence is strong. Sample collected by Peter Warwick, USGS. The two values in the statistics refer to A and B samples, respectively, analyzed for repeatability test

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LEGEND

Code: refers to the sample code as distributed for the round robin exercises

ICCP WG: name of the WG in which the exercise was run

Microscopy images: Please indicate in the image as much information as possible regarding illumination conditions and identification of components. If you use fluorescence and white light images. Insert them as a single image.

<u>Histogram with reflectance readings:</u> Please build up an histogram with the individual vitrinite reflectance means reported by participants to represent the scatter of the readings in the exercise

Report: indicate the name of the report in which the results of this sample are available as recorded in the webpage (i.e. Bostick 1982; Borrego 2006, etc...)

Participants N: number of results included in the exercise

Group mean (VRr %): refers to the group mean resulting of averaging the individual mean reflectance values reported by participants.

Group Stdv: refers to the group standard deviation resulting from the individual mean reflectance values reported by participants.

<u>Averaged Unsigned Multiple Stdv.</u>: refers to the Average value of the individual Unsigned Multiple of the Standard Deviations, calculated for each participant against the group mean and group standard deviation data. This statistical is used in the ICCP Accreditation Programms to assess the precision of the participants. Average Unsigned Multiple Stdv.=Summa(absolute value [participant VRr-Group Mean)/Group Stdv.])

<u>Coefficient of Variation</u>: allows comparing the dispersion of results regardless the value of the mean. Coefficient of variation=Group Stdv *100/ Group Mean.

<u>Scattering Index</u>: allows an estimation of the reliability of the values based on the Coefficient of Variation and the number of participants. Scattering Index=Coefficient of Variation/N of participants

<u>Comments:</u> Please indicate whatever information you consider relevant. Information to include is: objectives of the working group, indication about fluorescence properties, abundance of vitrinite particles to be measured, difficulties in sample preparation or polishing, possibility of suppressed values, the main conclusions about the characterization of the samples.